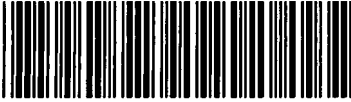


**Search Notes**

Application/Control No.

10/719,539

Examiner

Tan V. Mai

Applicant(s)/Patent under  
Reexamination

LIN ET AL.

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
708	300,301-323	6/13/2007	MAI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	6/13/2007	MAI